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CRYSTAL SPECIFICATION

Customer	:		
Customer P/N	:		
Agent	:		
Agent Code	:		
SIWARD P/N	:	XTL571200-A304-002	

Customer Approval :

希華晶體科技股份有限公司 SIWARD CRYSTAL TECHNOLOGY CO., LTD.

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2018/03/12 •

Approved By

Checked By

Designer

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Rev.	Description of Revision History	Date	Designer	Checked By
Rev. 1 2	Description of Revision History New Publication Tolerance Changed +/- 20 PPM to +/- 10 PPM ; Stability Over Temperature Changed +/- 30 PPM to +/- 20 PPM. (101K1803-006)	Date 2014/12/03 2018/03/09	Designer Sally Lin Sally Lin	Checked By Tom Tang Tom Tang



CRYSTAL SPECIFICATION

1.	Description	:	Quartz Crystal
2.	Nominal Frequency	:	27.000000 MHz
3.	Center Frequency	:	27.000000 MHz
4.	Dimension & Drawing No.	:	CSX-3225 ; SXD-00312
5.	Oscillation Mode	:	Fundamental
6.	Cutting Mode	:	AT cut
7.	Packing Style	:	TP-160
8.	Measurement Instrument	:	S&A 250B(Measured FL)

:

9. Electrical Characteristics [1] Operating Conditions :

Item	Symbol	MIN.	TYP.	MAX.	Unit	Condition
Operating Temperature Range	Topt	-40		85	°C	
Storage Temperature Range	Tstg	-40		90	°C	
Load Capacitance	CL		10		pF	
Drive Level	DL			100	μW	

[2] Frequency Stability :

Item	Symbol	MIN.	TYP.	MAX.	Unit	Condition
Tolerance	dF/Fo	-10		10	ppm	Refer to Center Frequency @25±3°C
Stability Over Temperature	dF/F25	-20		20	ppm	Refer to Operating Temperature
Aging	dF/F25	-3		3	ppm	Per Year

dF/Fo: Frequency Deviation Refer to Center Frequency

dF/F25: Frequency Deviation Refer to 25 $^\circ\!\mathrm{C}$ Frequency



[3] Electrical Performance :

Item	Symbol	MIN.	TYP.	MAX.	Unit	Condition
Equivalent Series Resistance	ESR			60	Ω	@Series
Shunt Capacitance	C0			5	pF	
Insulation Resistance	IR	500			MΩ	@DC 100 Volt

10. Marking : Laser

*MARKING : D ->YEAR C -> MONTH	
YEAR : 1 2 3 4 5 6 7 8 9 0 CODE : A B C D E F G H J K	27.0
MONTH: 1 2 3 4 5 6 7 8 9 10 11 12	S DC
CODE : A B C D E F G H J K L M	

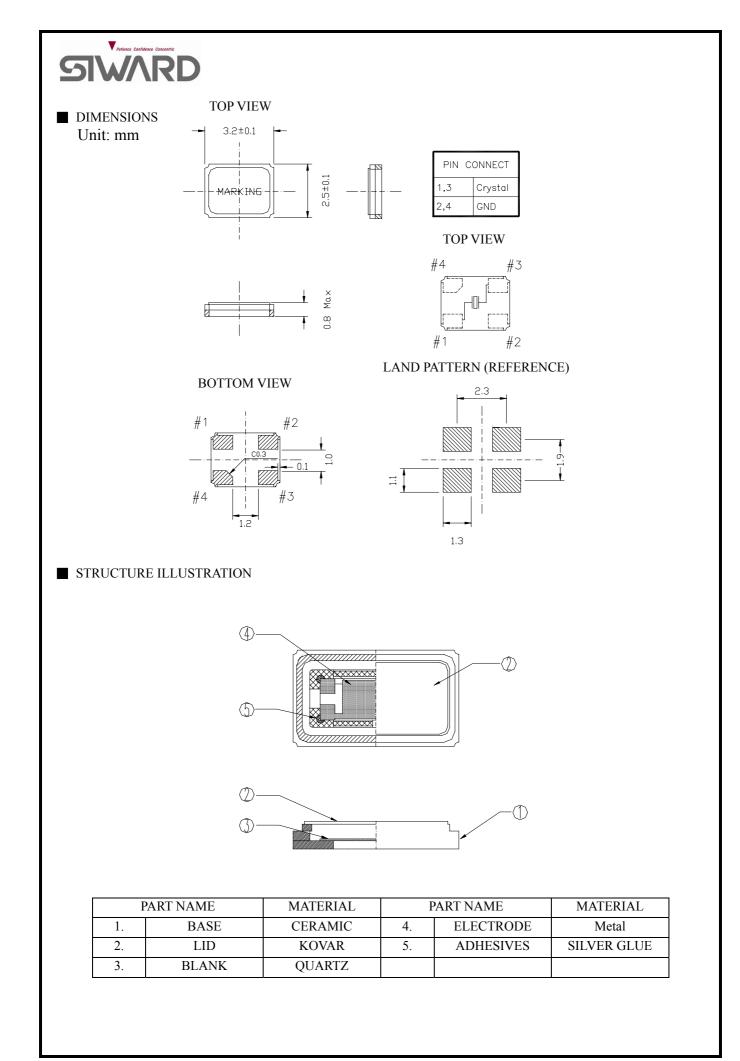
11. Remark :

* The component complies with Moisture Sensitivity Level 1 defined on JEDEC J-STD-020 standard. * Compliant with RoHS and Siward QAD-S-116 Standard.

■Note

1.General cleaning solutions or ultrasonic cleaning method may be used to clean our products. However, under certain circumstances, ultrasonic cleaning machine could generate resonance at the oscillaton frequency of our products and thus deteriorate the electrical characteristics in devices, and even damage the overall structure of devices. Therefore, verification test is recommended before cleaning.

2. Avoid mounting and processing by Ultrasonic welding this method has a possibility of an excessive vibration spreading inside the crystal products and becoming the cause of characteristic deterioration and not oscillating.





RELIABILITY SPECIFICATION

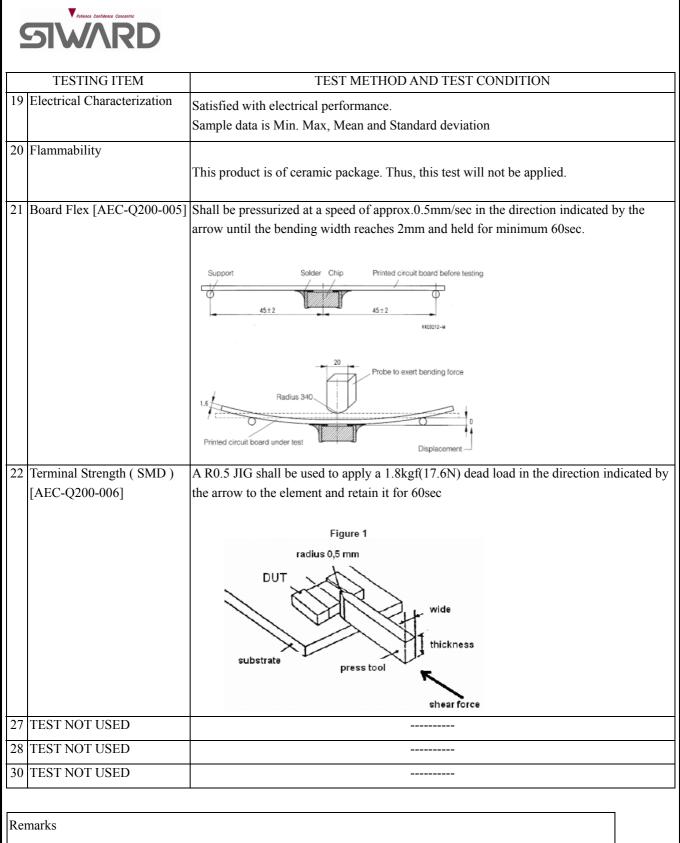
REFER TO Group A :

AEC-Q200-REV.D Conforming TABLE11-TABLE OF METHOD REFERENCED FOR QUARTZ CRYSTAL

	ELECTRICAL & MECHANI	CAL PERFORMANCE
	TESTING ITEM	TEST METHOD AND TEST CONDITION
1	Pre-and Post-Stress Electrical	Test equipment for crystal unit.
	Test	Test equipment for crystar unit.
2	TEST NOT USED	
2	High Temperature Exposure	The sector $r_{\rm c} + 105^{\circ}$
3		Temperature : $+125^{\circ}C$
	(Storage)	Time : 1000 hours
		Measurement at 24±4hours after test conclusion.
4	Temperature Cycling	Temperature Range : -40° C to $+125^{\circ}$ C
	[JESD22-Method JA104]	Cycle : 1000 cycles
		1 min. maximum transition time.
		+125°C
		125%
		+25°C
		-40°C
		30min
		← lcycle→
		Measurement at 24±4hours after test conclusion.
5	TEST NOT USED	
6	TEST NOT USED	
7	Biased Humidity	Townseture 1.05° C
/		Temperature : +85°C
		Humidity : 85%RH
		Time : 1000 hours Tested by oscillation.
		Measurement at 24±4hours after test conclusion.
8	Operational Life	Temperature : +125°C
	[MIL-STD-202 Method 108]	Time : 1000 hours
		Tested by oscillation
		Measurement at 24±4hours after test conclusion.
9	External Visual	
	[MIL-STD-883 Method	Inspect device construction, marking and workmanship. Electrical Test not required.
	2009]	
10	Physical Dimension	As per the specification shown on the drawing
	[JESD22 Method JB-100]	of external view and dimension.
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	TESTING ITEM	TEST METHOD AND TEST CONDITION
11	Terminal Strength (Leaded)	This product is of ceramic package. Thus, this test will not be applied.
12	Resistance to Solvents [MIL-STD-202 Method 211]	Solvent solutions : IPA (Level A or B) With IPA , to scrub the surface of the subject with the brush for 10 times .
13	Mechanical Shock	Test ConditionTest MethodHalf sine waveIn accordance withPeak value:3000G,0.3ms[MIL-STD-202Method 213]X,Y,Z each direction 1time
14	Vibration [MIL-STD-202 Method 204]	Frequency : 10-55HzAmplitude : 1.5mmFrequency : 55-2000HzPeak value : 20GDuration time: 4H for each X,Y,Z axisTotal 12hours
15	Resistance to Soldering Heat [MIL-STD-202 Method210]	Test condition : B Solder bath Temperature : $260\pm5^{\circ}$ C Time : 10 ± 1 sec.
16	TEST NOT USED	
17	TEST NOT USED	
18	Solderability [J-STD-002]	Perform test as per this reflow profile for one cycle. 10sec. 10sec. 45°C 150°C 150°C $90 \pm 30 \text{sec.}$



For the criteria of group A, please refer to the following test measurement items.

Satisfying electrical performance. Shall be free from any defectiveness on its surface after the test. If there is no special requirement, firstly the x'tal unit go through twice reflow, then measured secondly, the x'tal units go through the test. thirdly after the test, the x'tal units are kept for more then 24 hours at room temperature (25° C) and humidity. Lastly, the measurement is carried out.



RELIABILITY SPECIFICATION

REFER TO Group B :

Reliability Test, Leak parameter, Drop test

ELECTRICAL & MECHANICAL PERFORMANCE

ELECTRICAL & MECHANICAL PERFORMANCE				
TESTING ITEM	TEST METHOD AND TEST CONDITION			
Low Temperature Storage	Temperature : -40°C Time : 1000 hours			
Sealing	a) Gross leak (Air leak test) b) Fine leak (Helium leak test) He-pressure : 6kgf/cm ² 2Hours.			
Free Fall	Fall height : 150cm Weight : 50g Fall times : 10 times for Standard application. 100 times for Keyless entry On concrete plane.			
	TESTING ITEM Low Temperature Storage Sealing			

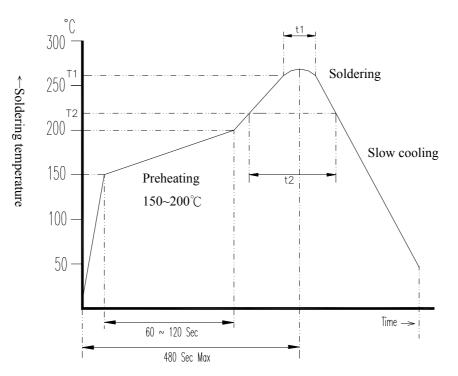
Notes : TESTING ITEM 9 \ 10 and 19 were tested in the process of manufacture.

Remarks

For the criteria of group B, please refer to the following test measurement items.

Satisfying electrical performance. Shall be free from any defectiveness on its surface after the test. If there is no special requirement, firstly the x'tal unit go through twice reflow, then measured secondly, the x'tal units go through the test. thirdly after the test, the x'tal units are kept for more then 24 hours at room temperature $(25^{\circ}C)$ and humidity. Lastly, the measurement is carried out.

■ SUGGESTED REFLOW PROFILE



Application\Temperature Time	T1 / t1	T2 / t2
Lead Free	$260\pm5^{\circ}$ C / 10 ±5 Sec Max	217°C Min / 60~150 Sec
Non Lead Free	$240\pm5^{\circ}$ C / 10 ±5 Sec Max	183°C Min / 60~150 Sec

